

The Reliability and Maintainability Symposium (RAMS)

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During the week of January 26-30, 2015, I had the honor and great pleasure of representing you and the International System Safety Society at the 61st Annual Reliability and Maintainability Symposium (RAMS) in Palm Harbor, Florida. I was there not only to attend the various paper presentations and tutorials, but to market our Society.

The Reliability and Maintainability Symposium is an annual event, and this year's RAMS was attended by more than 430 personnel from 30 countries. The symposium is coordinated and executed by the RAMS Management Committee, with oversight provided by the RAMS Board of Directors. The Board comprises representatives from the following organizations:

- American Institute of Aeronautics and Astronautics (AIAA)
- American Society for Quality (ASQ) Reliability Division
- American Society for Quality (ASQ) Electronics and Communications Division
- Institute of Environmental Sciences and Technology (IEST)
- Institute of Industrial Engineers (IIE) Quality Control and Reliability Engineering Division
- International System Safety Society (ISSS)
- Society of Automotive Engineers (SAE) International
- Society of Reliability Engineers (SRE)
- Institute of Electrical and Electronics Engineers (IEEE) Reliability Society

The Management Committee comprises several committees, which include the:

- Administration Committee
- Programs Committee
- Tutorial Committee
- Publicity Committee
- Arrangements Committee
- Registration Committee

There are also two paid consultants responsible for exhibitors and for ensuring that papers are properly formatted for the program.

The symposium also hosts an exhibitor's area and, during my four days there, I visited the booths of all vendors, which included:

- Advanced Logistics Development
- BQR
- Cochlear Limited
- COGOTO – Cutting Edge Engineering Solutions
- Controls and Data Services
- DfRSoft
- Defense Systems Information Analysis Center
- Fulton Findings
- HCRQ
- HI-REL Products
- IEEE
- Isograph, Inc.
- James Madison University
- Life Cycle Engineering
- Minitab, Inc.
- Modern Technology Solutions Inc.
- Omnicon Group Inc.
- Ops A La Carte
- Qualmark
- ReliaSoft Corporation
- SAS Institute Inc., World Headquarters
- Safety Tools Development
- Science and Technology Corporation
- Sierra Nevada Corporation – Space Systems
- Softrel, LLC
- SystraThingWorx
- UE Systems Inc.
- University of Arkansas
- University of Dayton
- University of Maryland

The annual symposium is focused on presenting training, tutorials and the latest technical practices in an easy-to-use format. The symposium brought together product assurance professionals with system safety professionals from around the world with the focus of delivering information, training and techniques applicable to government and commercial industries. The topics included:

- Human Factors Engineering
- Safety in Industrial Applications
- Safety Applications in High-Value Systems
- Introduction to Fault Tree Analysis (FTA)

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- Fundamentals of Failure Modes and Effects Analysis (FMEA)
- Reliability Growth Theory and Application
- Probabilistic Risk Assessment (PRA)

After reviewing the list of topics above, you will likely conclude that attendance at RAMS will benefit any system safety professional. I highly recommend that you, as a system safety professional, attend. RAMS is scheduled in January of each year, which does not conflict with attending our annual International Sys-

tem Safety Conference (ISSC). Additionally, the costs of attending RAMS are very similar to the costs of attending the ISSC. The benefit of attendance at RAMS may not be measurable in dollars and cents, but attendance will result in a more educated system safety professional resolving government and industry system safety issues.

The 62nd Annual RAMS is scheduled for January 25-28, 2016 at the Loews Ventana Canyon Resort in Tuscon, Arizona. The link to this event is posted on the Society Web site. ●